

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 251076US2DIV	SERIAL NO. 10/863, 038				
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Yuuichi HIRANO, et al.					
		FILING DATE Herewith 3/31/04	GROUP <del>Not Assigned</del> 2815				
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Q. H.	AA	5,373,170	12-1994	Pfiester et al.	257	69	
	AB	5,422,499	08-1995	Manning, Monte	257	67	
	AC	6,020,242	02-2000	Tsal et al.	438	279	
	AD	6,429,124	08-2002	Tang et al.	438	643	
Q. H.	AE	5,395,783	03/07/1995	R.C. Baumann, et al.	438	239	
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION	
						YES	NO
Q. H.	AO	6-188388	07/08/94	Japan (with English abstract)	CLASS 546.1		X
	AP	5-235301	09/10/93	Japan (with English abstract)			X
	AQ	690 09 157	09/08/1994	Germany (with corr. EP 0 432 057)			X
Q. H.	AR	0 432 057	06/12/1991	Europe			X
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
Q. H.	AW	Ross A. KOHLER, et al. "SEU CHARACTERIZATION OF HARDENED CMOS SRAMS USING STATISTICAL ANALYSIS OF FEEDBACK DELAY IN MEMORY CELLS", IEEE Transactions on Nuclear Science, Vol 36, No. 6, December 1989, pages 2318-2323.					
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner Q. H.					Date Considered 9/27/04		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 1 OF 1

Form PTO 1449  
(Modified)DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
251076US2DIVSERIAL NO.  
10/813,038

## LIST OF REFERENCES CITED BY APPLICANT

## APPLICANT

Yuichi HIRANO, et al.

## FILING DATE

March 31, 2004

## GROUP

2815

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>CAU</i>	AA	5,338,963	08/16/1994	Klaasen et al. (corresponding to JP 7-7089)	—	—	—
<i>Wdl</i>	AB	4,956,815	09/11/1990	Houston	—	—	—
	AC						
	AD						
	AE						
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	AH						
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	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>CAU</i>	AO	11-67933	09/03/1999	JAPAN (w/English abstract)		X
<i>Wdl</i>	AP	2001-189389	10/07/2001	JAPAN (w/English abstract)		X
<i>Wdl</i>	AQ	7-7089	10/01/1995	JAPAN		X
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

*a. W. Wil*

Date Considered

11/18/04

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.